Special Issue

Deep Learning in Medical Image Processing and Analysis

Message from the Guest Editors

Recently, deep learning (DL) techniques have revolutionized the field of medical image processing, enabling automated analysis of medical images and enhancing the accuracy and efficiency of clinical diagnosis. The use of DL in medical image processing has significantly improved the detection, classification, and segmentation of various pathological conditions, leading to improved patient outcomes. Therefore, the application of DL in medical image processing in clinical settings is becoming increasingly common.

Guest Editors

Prof. Dr. Jiann-Der Lee
Department of Electrical Engineering, Chang Gung University, Tao-Yuan 33302, Taiwan

Dr. Jong-Chih Chien
School of Informatics, Kainan University, Tao-Yuan 33857, Taiwan

---

Deadline for manuscript submissions

20 November 2025

Applied Sciences

an Open Access Journal by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/si/205467

Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

mdpi.com/journal/applsci

MDPI

Applied Sciences

an Open Access Journal
by MDPI

Impact Factor 2.5
CiteScore 5.5

mdpi.com/journal/applsci

MDPI

About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,
20133 Milano, Italy

Author Benefits

Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, CAPlus / SciFinder, and other databases.

Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering)